

FORM PTO-1449		Atty Docket: 31583-165338		Application No.: 09/622,278	
INFORMATION DISCLOSURE STATEMENT		Applicant: Matthias HARTRUMPF			
		Filing Date: August 15, 2000		Group: 5071 2878	

U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
SCS	AA	4,201,476	May 6, 1980	Musto et al.	356	386	1-5-78
SCS	AB	4,124,728	November 7, 1978	Marcuse et al.	427	8	1-31-77
SCS	AC	4,408,884	October 11, 1983	Kleinknecht et al.	356	355	6-29-81
SCS	AD	4,432,648	February 21, 1984	Musto et al.	356	387	5-18-81
SCS	AE	4,748,332	May 31, 1988	Kühne et al.	250	560	3-5-87
SCS	AF	4,778,271	October 18, 1988	Kuwabara et al.	356	386	3-13-87
SCS	AG	5,335,057	August 2, 1994	Shaw et al.	356	73.1	9-8-92
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-Class	Translation Yes <input type="checkbox"/> No <input type="checkbox"/>
SCS	AL	1 498 227 ✓	January 18, 1978	UK	G01B	11/00	
SCS	AM	DE 2657938 C2 ✓	May 3, 1989	Germany	G01B	11/02	X
SCS	AN	DE 3526656 A 1 ✓	February 6, 1986	Germany	G01B	11/02	X
SCS	AO	DE 3623318 A 1 /	January 21, 1988	Germany	G01B	11/02	X
SCS	AP	DE 3820170 A 1 ✓	December 21, 1989	Germany	G01J	9/02	X
SCS	AQ	DE 4114786 A 1 ✓	November 12, 1992	Germany	G01P	13/00	X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
	AR	
	AS	
	AT	

Examiner: <u>Seung C. Sohn</u>	Date Considered: <u>1-16-2002</u>
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EXAMINER:	Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.
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	AA						
	AB						
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	AH						

FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-Class	Translation Yes <input type="checkbox"/> No <input type="checkbox"/>
SCS	AI	DE 4134148 A 1 ✓	April 22, 1993	Germany	G01B	11/02	X
SCS	AI	DE 19621709 A 1 ✓	December 4, 1997	Germany	G01B	11/00	X
SCS	AK	0 416 362 A2 ✓	March 13, 1991	EPO	G01N	21/47	X
SCS	AL	0 439 802 A2 ✓	August 7, 1991	EPO	G01B	11/02	X
SCS	AM	0 439 803 A2 ✓	August 7, 1991	EPO	G01B	11/08	X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
SCS	AN	K.-S. Chang et al., "Correction Algorithms in a Laser Scanning Dimension Measurement System", in 8049a IEE Proceedings-A, 139 (1992) March, No. 2, Part A, Stevenage, Herts, Great Britain
	AO	
	AP	

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